

SEMI F47
Voltage Sag Immunity Test Report
for
Power Supply CP10.241-ETC



Other devices covered by this report:

CP10.248

Unit with build-in display

SEMI F47 Test Report

Document number	CP10.241-ETC Semi F47 Rev1 TR1
PCTM number	PCTM-27 (1)
Standards	SEMI F47-0706 (July 2006) SPECIFICATION FOR SEMICONDUCTOR PROCESSING EQUIPMENT - Voltage Sag Immunity Compliance Tests IEC 61000-4-11 2004 +A1:2017 Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current up to 16 A per phase
Applicant	PULS GmbH Elektrastraße 6 81925 Munich, Germany
Test Laboratory	PULS Vario GmbH Kranichberggasse 6 1120 Vienna, Austria
Test Engineer	Thomas Ramel, Daniel Schwayer
Test Date	29.08.2023
Description of Test Device:	Built-in power supplies for DIN-Rail mounting
Devices under Evaluation:	CP10.241-ETC Input: AC 100-240V, DC 110-150V, Output: DC 24-28V, 10A
S/N of Devices:	CP10.241-ETC: S/N: 25955010 A
Application Details:	Input voltage: 1-Phase AC 208V Input frequency: 50 or 60Hz Output load: 240W

PASS/FAIL Criteria:

In accordance with paragraph 7.8.2 a) of SEMI F47-0706
The output voltage is not allowed to deviated more than 5% of the initial value.

Test Result:

PASS

The test device passed all essential SEMI F47-0706 tests according to the defined application details without any limitations and is qualified to bear the following approval mark:



Since DC power supplies, as covered in this test report, are only components of a semiconductor processing equipment, the tests of the SEMI F47 standard were conducted with selected rated characteristics of the DC power supply.

The system integrator of the final semiconductor processing equipment needs to judge if the results of this test report are compatible with the SEMI F47 requirements of his system or if test data under other operating conditions are additionally required.

The system integrator also needs to judge if the results of the inrush current peaks are compatible with the selected external fuses for input protection.

The system integrator also needs to be aware about aging effects. It is expected that the ride through time can be reduced by 15% at end of the specified lifetime expectancy.

A SEMI F47 certificate is not intended for this type of component, however the product fulfils the general requirements and can be marked with the following symbol.

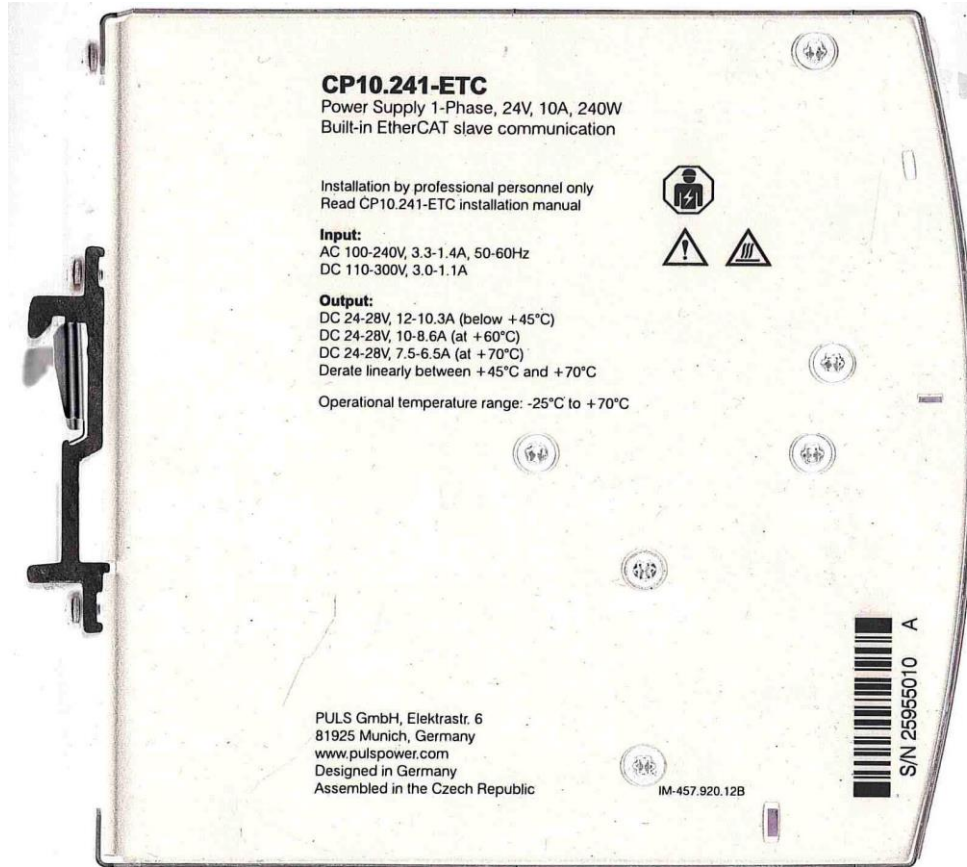
Approved

Harald Etlinger
Sr. Qualification Eng.
PULS Vario GmbH, Vienna

Date of Approval

01.09.2023

Copy of marking plate:



List of Test Equipment

Type	Model	Inventory number
Test generator:	Kikusui PCR3000WE2	10372
Load:	Chroma 63201 - 2.6kW	10054
Oscilloscope:	LeCroy WS454	10129
Oscilloscope:	LeCroy WS454	10127
Differential probe.	LeCroy AP031	10259
Current Probe:	LeCroy CP150	10280
Communication Interface:	EtherCAT Testdevice	(MUC) 800.20 [2]

The test equipment complies with the requirements of IEC 61000-4-11.

The peak current capability of the test generator was evaluated according Annex A of IEC 61000-4-11 and is able to deliver minimum 32.7A.

Test Specification for SEMI F47 compliance

Voltage Sag Immunity according to the following table:

Sag depth#1	Duration	Duration at 50 Hz	Duration at 60 Hz
50%	200ms	10 cycles	12 cycles
70%	500ms	25 cycles	30 cycles
80%	1000ms	50 cycles	60 cycles

#1 Sag depth is expressed in percent of remaining nominal voltage. For example, during a 70% voltage sag on a 200 volt nominal system, the voltage is reduced during the sag to 140 volts and not 60 volts.

Test Setup

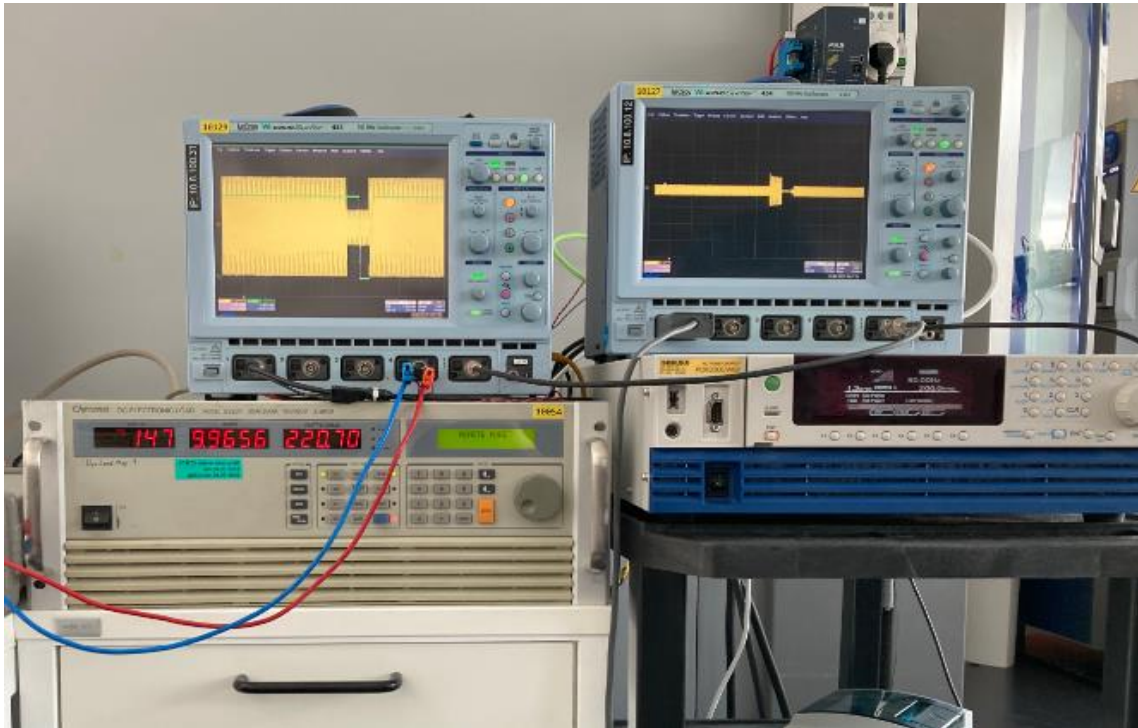
The unit under test in normal operating condition mounted in climate chamber.

The input is connected to an AC Source. The input voltage is measured with a 100:1 differential probe and the input current is measured with current probes. These probes are connected to oscilloscopes.

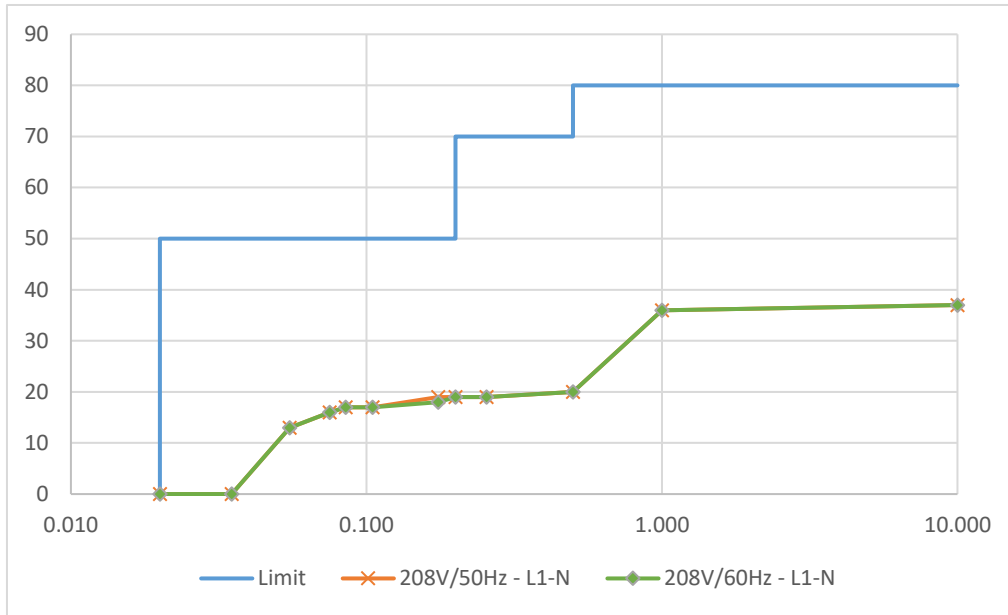
The output is connected to an active load. The output voltage is connected directly to the oscilloscope.

Input and output voltages are measured with oscilloscope #1 and input currents with oscilloscope #2.

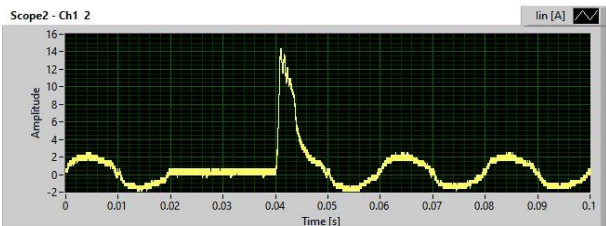
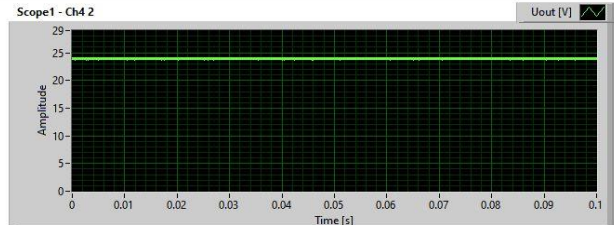
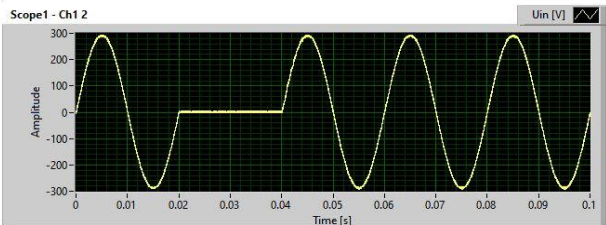
Active EtherCAT communication is simulated with the "EtherCAT Testdevice 800.20 [2]" during the tests.



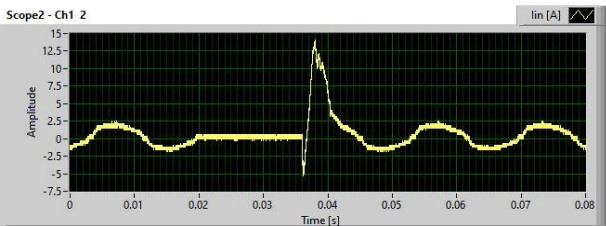
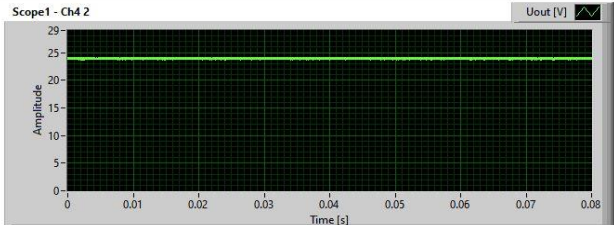
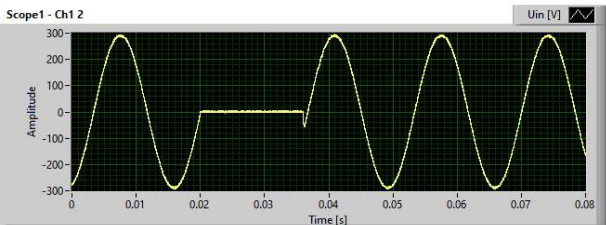
Voltage Sag Results



25°C Norm 208V 50Hz 0.020s 0% L1-N 0°



25°C Norm 208V 60Hz 0.016s 0% L1-N 0°



Conducted Tests at 208V 50Hz

Input voltage 208Vac
 Input Frequency 50Hz
 Output voltage 24V
 Output current 10A
 Ambient temperature 25°C

Sag duration [s]	Voltage remaining [%]	Positive peak current	Negative peak current
0.020	0	14.4	-1.9
0.200	50	6.2	-4.1
0.500	70	3.7	-2.8
1	80	3.1	-2.5
10	80	2.8	-2.5

Informational measurements

Sag duration [s]	Voltage remaining [%]
0.020	0
0.035	0
0.055	13
0.075	16
0.085	17
0.105	17

Sag duration [s]	Voltage remaining [%]
0.175	19
0.200	19
0.255	19
0.500	20
1	36
10	37

Conducted Tests at 208V 60Hz

Input voltage 208Vac
 Input Frequency 60Hz
 Output voltage 24V
 Output current 10A
 Ambient temperature 25°C

Sag duration [s]	Voltage remaining [%]	Positive peak current	Negative peak current
0.016	0	14.1	-5.3
0.200	50	6.6	-4.1
0.500	70	3.7	-2.8
1	80	3.1	-2.2
10	80	2.8	-2.5

Informational measurements

Sag duration [s]	Voltage remaining [%]
0.016	0
0.035	0
0.055	13
0.075	16
0.085	17
0.105	17

Sag duration [s]	Voltage remaining [%]
0.175	18
0.200	19
0.255	19
0.500	20
1	36
10	37

Inrush current measurements according 61000-4-11 at 208V 50Hz

Input voltage	208Vac
Input Frequency	50Hz
Output voltage	24V
Output current	10A
Ambient temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°: 7.2

Measure peak input current when AC turned on at 270°: 6.2

Next two measurements turn on the input power for EUT for at least 1 minute then turn off input power for 5s and on again.

Measure peak input current when AC turned on at 90°: 6.6

Measure peak input current when AC turned on at 270°: 6.6

Inrush current measurements according 61000-4-11 at 208V 60Hz

Input voltage	208Vac
Input Frequency	60Hz
Output voltage	24V
Output current	10A
Ambient temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°: 6.6

Measure peak input current when AC turned on at 270°: 5.9

on again.

Measure peak input current when AC turned on at 90°: 6.2

Measure peak input current when AC turned on at 270°: 6.2

Operating conditions and their influence in test results:

a) Ambient temperature:

Control measurements show that the ambient temperature has only a minor influence in the ride-through time test results.

Depending on the used topology to reduce the input inrush current, the ambient temperature can have a major influence in the arising peak current after the sag test. Therefore, tests were performed at ambient temperatures of 25°C and +60°C.

It is assumed that semiconductor processing equipment is never used at lower temperatures than +25°C. Although the power supply itself is specified down to -25°C, a test at such low temperatures is not performed.

b) Mains frequency 50Hz vs. 60Hz:

Control measurements show that 50Hz testing is more critical than 60Hz testing.

Therefore, unless otherwise noted, all tests were performed with a mains frequency of 50Hz.

c) Output voltage 24V vs. 28V:

The ride-through time depend on the stored energy in the input capacitors and the amount of output power. The output voltage is not essential as long as the output power is constant.

The adjusted output voltage has no influence in input currents peaks after input voltage sags.

Therefore, unless otherwise noted, all tests were performed with an output voltage of 24Vdc.

APPENDIX

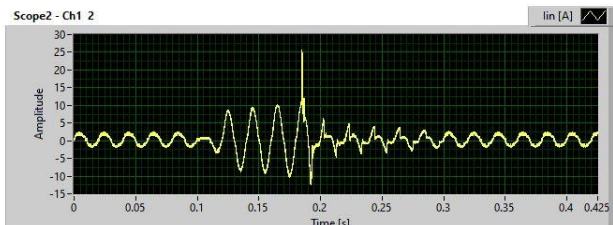
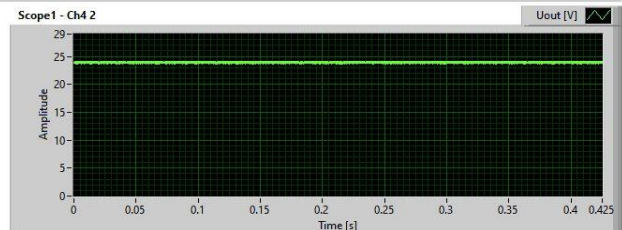
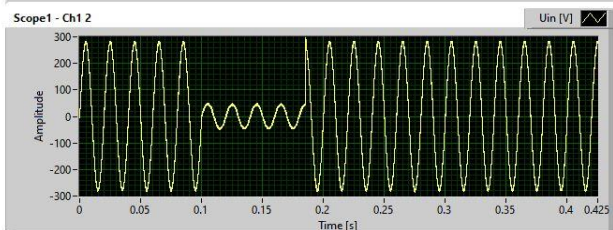
Informational measurements at 200V

Input voltage 200Vac
 Input Frequency 50Hz
 Output voltage 24V
 Output current 10A
 Ambient temperature 25°C

Informational measurements

Sag duration [s]	Voltage remaining [%]	Positive peak current [A]	Negative peak current [A]
0.020	0	14.7	-2.2
0.035	0	12.8	-24.1
0.055	14	13.1	-25.6
0.075	17	13.1	-24.7
0.085	17	25.6	-12.5
0.105	18	24.7	-12.5
0.175	19	12.5	-23.4
0.200	19	16.6	-11.9
0.255	20	12.5	-23.1
0.500	20	15.6	-11.6
1	38	11.6	-5.6
10	38	11.9	-5.6

25°C 200V 50Hz 0.085s 17% L1-N 0°



Informational measurements at 230V

Input voltage 230Vac
 Input Frequency 50Hz
 Output voltage 24V
 Output current 10A
 Ambient temperature 25°C

Informational measurements

Sag duration [s]	Voltage remaining [%]	Positive peak current [A]	Negative peak current [A]
0.020	0	14.7	-1.9
0.035	0	6.2	-26.6
0.055	12	12.2	-26.9
0.075	15	13.4	-27.2
0.085	15	25.6	-13.4
0.105	16	25.6	-13.4
0.175	17	13.4	-25
0.200	17	16.2	-11.2
0.255	17	13.7	-25.6
0.500	18	15.9	-10.9
1	33	12.5	-5.9
10	33	12.2	-5.6

25°C 230V 50Hz 0.075s 15% L1-N 0°

